

Erratum: “Calibration of atomic-force microscope tips” [Rev. Sci. Instrum. 64, 1868 (1993)]

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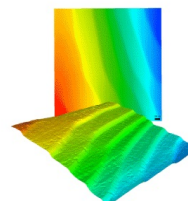
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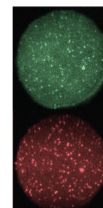
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Erratum: "Calibration of atomic-force microscope tips" **[Rev. Sci. Instrum. 64, 1868 (1993)]**

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In our calibration of atomic-force microscope cantilevers, we neglected to correct for the frequency response of the optical-detection electronics. The response to cantilever vibrations will have a high-frequency cut-off, which, in our case, was higher than the resonant frequency of the cantilever. Our results were not affected, but for higher resonant frequencies, one should calibrate the detector response. We thank V. Croquette for raising this point.